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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant	: Shunpei Yamazaki et al.	Art Unit	: 2829
Serial No.	: 10/685,398	Examiner	: Luan C. Thai
Filed	: October 16, 2003	Confirmation No.:	
Title	: SEMICONDUCTOR APPARATUS AND FABRICATION METHOD OF THE SAME		

MAIL STOP AMENDMENT
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), copies of the listed U.S. patents and U.S. patent application publications are not attached and can be provided upon request.

This statement is being filed within three months of the filing date of a request for continued examination. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 9/14/05

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Substitute Form PTO-1449 (Modified) U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-168001	Application No. 10/685,398
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	Applicant: Shunpei Yamazaki et al.	
	Filing Date: October 16, 2003	Group Art Unit: 2829

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,821,138	10/13/1998	Yamazaki et al.			02/16/1996
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	AN	2005/0164470 A1	07/28/2005	Yamazaki et al.			03/15/2005

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation Yes	Translation No
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature	Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.